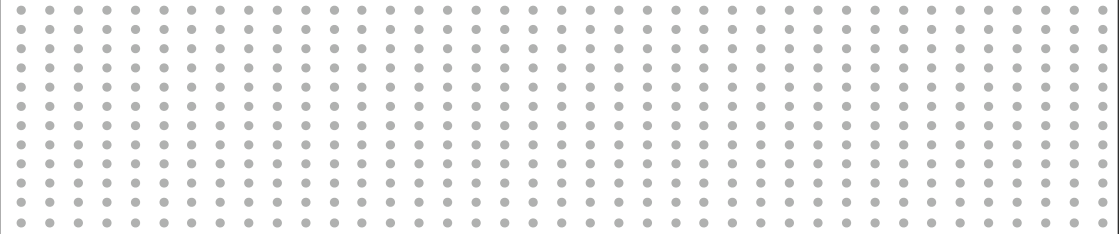


Testing
Innovation

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Our technology pillars enable us to consistently design and deliver Complete Solutions to ensure that our customers achieve greater test coverage and maximize their innovation's reliability and commercial success.

We use high-performance, high-density modular, Asynchronous Massively Parallel systems to test complex devices.

We have a unique and highly differentiated way of conducting System Level Test (SLT). Using an enhanced SLT, our customers can test

high-end semiconductor devices in either processors, automotive devices, or mobile devices with full coverage.

We offer our customers the ability to take the semiconductor devices in high-volume manufacturing and test them in parallel with a very large number of these devices so that customers can increase their throughput while they getting the test coverage that system-level testing provides.

Leveraging world-leading thermal capabilities, application specific testers, and intelligent handlers, AEM has delivered a paradigm -shifting solution to the world's semiconductor test needs.

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Steven Resnik
Account Manager - US
steven.resnik@aem.com.sg
M: 512-983-4000

AEM
52 Serangoon North Ave 4
Singapore 555853



AEM's approach to SLT enables increased coverage of the test flow

AEM's Test Cell Solutions span across Wafer Sort, Burn-in, Final Test and SLT

Wafer Sort

Burn In

Final Test

System Level Test

Innovative Testing Solutions vs Traditional Testing

The traditional approach of ATEs to test increasingly complex devices on advanced nodes has reached a point of diminishing returns as it gets exponentially more expensive to increase test coverage to acceptable levels. As devices become more complex and companies rapidly adopt heterogeneous packaging technologies, System Level Test becomes crucial in the entire test process.

AEM provides asynchronous, modular, highly parallel test cell solutions that enable each test cell to run SLT, final test, or burn-in all-in-one system and handle hundreds of test cells independently with each test cell testing multiple devices. Our solutions make the comprehensive testing of every complex device cost-effective. Without the burden of legacy ATE, we can provide innovative solutions for our customers.

Today, the only way to ensure safety, reliance, and test coverage is to use System Level Test. As pioneers of SLT, our customers are confident of partnering with us because we have a tremendous lead in deployment experience and technology.

Visit our blog :

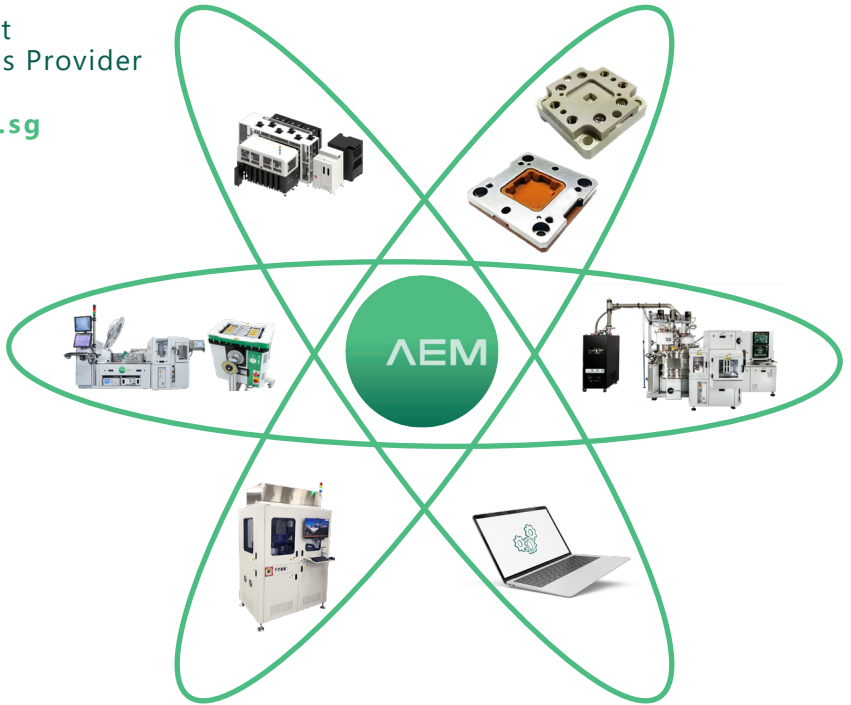
The Semiconductor Industry Needs Continuous Improved Faults Coverage While Reducing The Overall Cost Of Test. By Stuart Pearce, Senior Director, Field Marketing.



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